Se	arch Notes	;

Application/Control No.	Applicant(s)/Patent Reexamination	under
10/540,364	WEINHOLD, KARL	
Examiner	Art Unit	
David E. Bochna	3679	

	SEAR	CHED	
Class	Subclass	Date	Examiner
285	903	11/30/2007	DB
	409		
	252		
	254		
	253		
	419		
	420		
	411		
	373		
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· INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
285	903, 252	11/30/2007	DB	
	373, 419			
	420			
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SEARCH (INCLUDING SEAF	NOTE RCH ST	S FRATEGY)
		DATE	EXMR
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